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Examiner

Cong-Lac Huynh

Applicant(s)/Patent under Reexamination

BERGMAN ET AL.

Art Unit

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	SEARCHED		
Class	Subclass	Date	Examiner
715	530	6/18/2005	CLH
	500	6/18/2005	CLH
	864	6/18/2005	CLH
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East	6/	18/2005	CLH
ACM	6/	18/2005	CLH
IEEE	6/	18/2005	CLH
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